PROCEEDINGS OF SPIE

Vertical-Cavity Surface-Emitting Lasers XX

Kent D. Choquette James K. Guenter Editors

17–18 February 2016 San Francisco, California, United States

Sponsored and Published by SPIE

Volume 9766

Proceedings of SPIE 0277-786X, V. 9766

SPIE is an international society advancing an interdisciplinary approach to the science and application of light.

Vertical-Cavity Surface-Emitting Lasers XX, edited by Kent D. Choquette, James K. Guenter, Proc. of SPIE Vol. 9766, 976601 ⋅ © 2016 SPIE CCC code: 0277-786X/16/\$18 ⋅ doi: 10.1117/12.2239802

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Author(s), "Title of Paper," in *Vertical-Cavity Surface-Emitting Lasers XX*, edited by Kent D. Choquette, James K. Guenter, Proceedings of SPIE Vol. 9766 (SPIE, Bellingham, WA, 2016) Six-digit Article CID Number.

ISSN: 0277-786X

ISSN: 1996-756X (electronic) ISBN: 9781510600010

Published by

SPIE

P.O. Box 10, Bellingham, Washington 98227-0010 USA Telephone +1 360 676 3290 (Pacific Time) · Fax +1 360 647 1445 SPIE.org

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